10th International ”Hiroshima” Symposium on the Development and Application of Semiconductor Tracking Detectors, Xi’an, China

Contribution ID: **77** Type: **ORAL**

First result of a Double-SOI pixel chip for x-ray imaging

Sunday 27 September 2015 11:50 (20 minutes)

Aiming at a fine pitch counting type pixel array for low energy x-ray imaging, a prototype chip based on Double-SOI process was designed and tested. The long lasting problem of crosstalk in SOI technology was solved in this chip and the single pixel test demonstrated good detection performance.

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Session Classification: Pixels (including CCD’s)-2

Track Classification: Pixels (incl. CCD’s) - X-ray imaging